PREPARED BY: DATE:		SPEC. No. ED-00112
Y. Jourila June 13. 2005	SHARP	Government 13, 2000
APPROVED BY: DATE:	ELECTRONIC COMPONENTS	PAGE STATION
K. Husuda June 13, 2000	GROUP SHARP CORPORATION SPECIFICATION	N REPRESENTATIVE DIVISION OPTO-ELECTRONIC DEVICES DV.
	CE SPECIFICATION FOR PC8171 PHOTOCOUPLER PC8171 EL No. PC8171 PC8171 series PC817 PC8171 series PC817	11NSZ 12NSZ 13NSZ 15NSZ 16NSZ
Please do not reproduce or2. When using this product, p in these specification sheet	nclude materials protected under copyrigh cause anyone to reproduce them without S lease observe the absolute maximum ratin s, as well as the precautions mentioned be om use of the product which does not com	Sharp's consent. gs and the instructions for use outlined low. Sharp assumes no responsibility
 (Precautions) This product is defined OA equipment Telecommunice Tooling machine If the use of the properties of the properties of the properties of the properties of the safety design of and safety when the safety in function Transportation Traffic signals Other safety equipment (3) Please do not use and safety in function 	ed in these specification sheets, and the particular signed for use in the following application • Audio visual equipment • Home appli- ation equipment (Terminal) • Measuring hes • Computers product in the above application areas is for be sure to observe the precautions given in ures, such as fail-safe design and redundar of the overall system and equipment, should his product is used for equipment which do and precision, such as ; • control and safety equipment (aircraft, tra • Gas leakage sensor breakers • Rescu- puipment this product for equipment which require tion and precision, such as ; ent • Telecommunication equipment (for	areas ; iances equipment or equipment listed in paragraphs or those respective paragraphs. Int design considering Id be taken to ensure reliability emands high reliability and ain, automobile etc.) e and security equipment extremely high reliability
• Nuclear power (4) Please contact and	control equipment • Medical equipment i consult with a Sharp sales representative tation of the above three paragraphs.	
• • • •	with a Sharp sales representative for any o	questions about this product.
CUSTOMER'S APPROVA	AL DATE BY	June 13, 2000 NTED for X. Yuunda
DATE	De	Hachimura, epartment General Manager of ngineering Dept.,II
ВҮ	Or EL	ECOM Group JARP CORPORATION

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1. Application

This specification applies to the outline and characteristics of photocoupler Model No. PC8171 series.

2. Outline

Refer to the attached sheet, page 3.

3. Ratings and characteristics

Refer to the attached sheet, page 4 to 6.

4. Reliability

Refer to the attached sheet, page 7.

5. Outgoing inspection

Refer to the attached sheet, page 8.

- 6. Supplement
 - 6.1 Isolation voltage shall be measured in the following method.
 - (1) Short between anode and cathode on the primary side, and between collector and emitter on the secondary side.
 - (2) The dielectric withstand tester with zero-cross circuit shall be used.
 - (3) The wave form of applied voltage shall be a sine wave. (It is recommended that the isolation voltage be measured in insulation oil.)

Ordered product	Business dealing name	Rank mark	Ic (mA)	Test condi
	PC81710NSZ	A, B, C or no mark	0.5 to 3.0	I _F =0.
	PC81711NSZ	А	0.6 to 1.5	V _{CE} =
	PC81712NSZ	В	0.8 to 2.0	Ta=2
	PC81713NSZ	С	1.0 to 2.5	
	PC81715NSZ	A or B	0.6 to 2.0	
	PC81716NSZ	B or C	0.8 to 2.5	
	PC81718NSZ	A, B or C	0.6 to 2.5	

6.2 Collector current (Ic) Delivery rank table (" \bigcirc " mark indicates business dealing name of ordered product)

itions

).5mA =5V

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EFR

25℃

6.3 This Model is approved by UL.

Approved Model No. : PC8171

UL file No. : E64380

6.4 This product is not designed against irradiation.

This product is assembled with electrical input and output.

This product incorporates non-coherent light emitting diode.

6.5 ODS materials

This product shall not contain the following materials. Also, the following materials shall not be used in the production process for this product.

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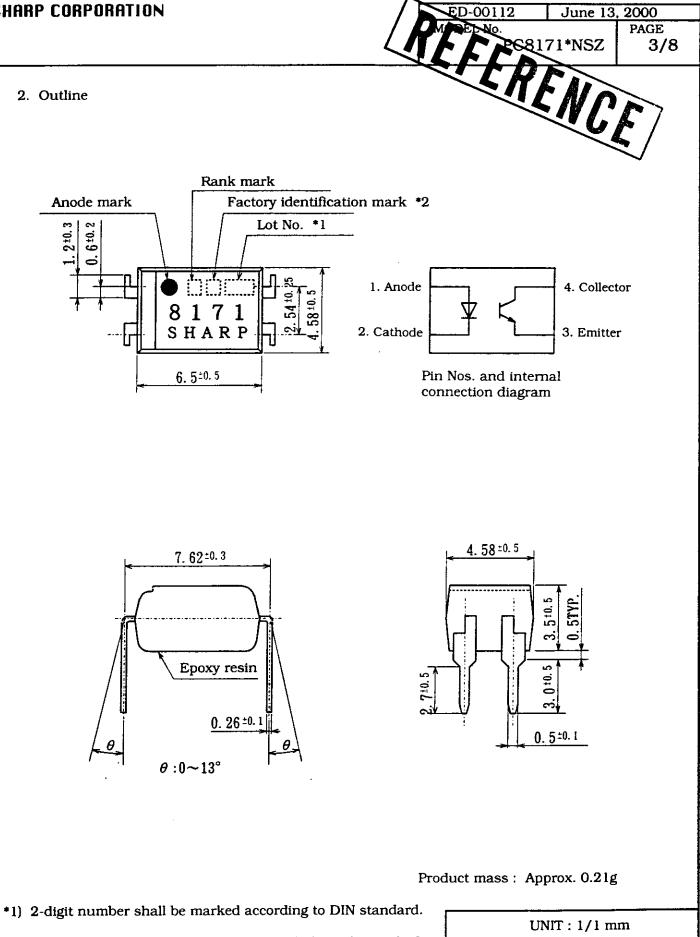
Materials for ODS : CFC_S, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

6.6 Brominated flame retardants

Specific brominated flame retardants such as the $\mbox{PBBO}_{\rm S}$ and $\mbox{PBB}_{\rm S}$ are not used in this device at all.

7. Notes

Refer to the attached sheets-1-1,2.



- *2) Factory identification mark shall be or shall not be marked.
- *3) Marking is laser marking

PC8171 **Outline Dimensions** Name (Business dealing name : PC8171*NSZ)

- 3. Ratings and characteristics
 - 3.1 Absolute maximum ratings

	Parameter	Symbol	Rating	Unit
*1 Forward current		I _F	10	mA
*2 Peak forward current Input Reverse voltage		I _{FM}	200	mA
		V _R	6	v
	*1 Power dissipation	Р	15	mW
	Collector-emitter voltage	V _{CEO}	70	v
Output	Emitter-collector voltage	V _{ECO}	6	v
Output Collector current		Ic	50	mA
	*1 Collector power dissipation	Рс	150	mW
*1 Total power dissipation		Ptot	170	mW
*3 Isolation voltage		Viso(rms)	5	kV
Operating temperature		Topr	-30 to +100	r
Storage temperature		Tstg	-55 to +125	Ů
*4 Soldering temperature		Tsol	260	Ĵ

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*1 The derating factors of absolute maximum ratings due to ambient temperature are shown in Fig. 1 to 4.

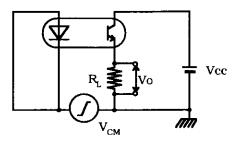
- *2 Pulse width $\leq 100 \,\mu$ s, Duty ratio : 0.001 (Refer to Fig. 5)
- *3 AC for 1 min, 40 to 60%RH

*4 For 10 s

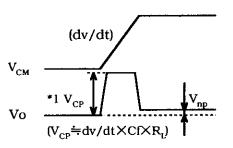
3.2 Electro-optical characteristics

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
	Forward voltage	V _F	I _F =5mA	-	1.2	1.4	v
Input	Reverse current	I _R	V _R =4V	-	-	10	μA
	Terminal capacitance	Ct	V=0, f=1kHz	-	30	250	pF
	Dark current	I _{CEO}	V _{CE} =50V, I _F =0	-	-	100	nA
Output	Collector-emitter breakdown voltage	BV _{CEO}	Ic=0.1mA I _F =0	70	-	-	v
	Emitter-collector breakdown voltage	BV _{ECO}	$I_{E} = 10 \ \mu A, \ I_{F} = 0$	6	-	-	v
	Collector current	Ic	I _F =0.5mA V _{CE} =5V	0.5	-	3.0	mA
	Collector-emitter saturation voltage	V _{CE(sat)}	I _F =10mA Ic=1mA	-	-	0.2	v
Transfer	Isolation resistance	Riso	DC500V 40 to 60%RH	5×10 ¹⁰	1011	-	Ω
charac-	Floating capacitance	Cf	V=0, f=1MHz	-	0.6	1.0	pF
teristics	Response time (Rise)	tr	V _{CE} =2V Ic=2mA	-	4	18	μs
Ī	Response time (Fall)	tf	$R_{L} = 100 \Omega$	-	3	18	μs
	Common mode rejection ratio *5	CMR	Ta=25°C, R_L =470 Ω V_{CM} =1.5kV(peak), I_F =0mA, Vcc=9V, Vnp=100mV	10	_	_	kV/µs

*5 Measuring circuit



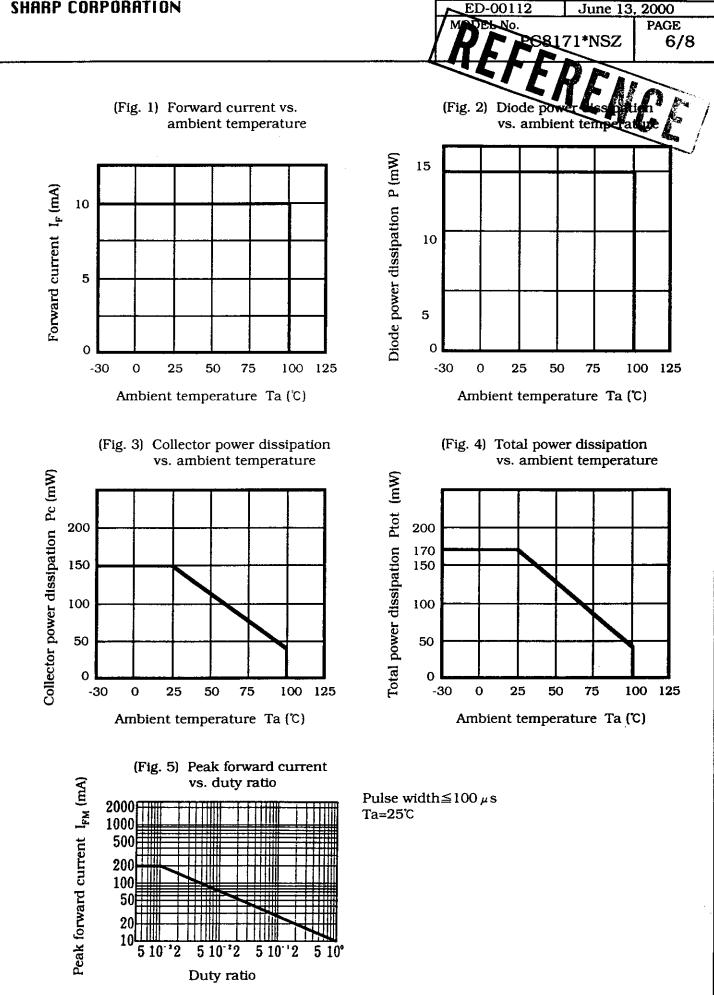
 V_{CM} : Higher value of pulse wave R_L =470 Ω Vcc=9V



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*1 The voltage generated by a displacement current which flow through floating capacity between primary and secondary side



4. Reliability

The reliability of products shall satisfy items listed below.

Confidence level : 90% LTPD : 10%/20%

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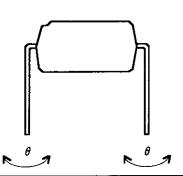
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Test Items	Test Conditions *1	Failure Judgement Criteria	Samples (n) Defective(C)
Solderability *2	230℃, 5 s	· · · · · · · · · · · · · · · · · · ·	n=11, C=0
Soldering heat	260℃, 10 s		n=11, C=0
Terminal strength (Tension)	Weight : 5N 5 s/each terminal	V _F >U×1.2	n=11, C=0
Terminal strength (Bending) *3	Weight : 2.5N 2 times/each terminal	$I_R > U \times 2$	n=11, C=0
Mechanical shock	15km/s ² , 0.5ms 3 times/±X, ±Y, ±Z direction	$I_{CEO} > U \times 2$ $I_{C} < L \times 0.7$	n=11, C=0
Variable frequency vibration	100 to 2000 to 100Hz/4min 200m/s ² 4 times/ X, Y, Z direction	V _{CE(sat)} >U×1.2	n=11, C=0
Temperature cycling	1 cycle -55°C to +125°C (30min) (30min) 20 cycles test	U : Upper	n=22,C=0
High temp. and high humidity storage	+60°C, 90%RH, 1000h	specification limit	n=22,C=0
High temp. storage	+125°C, 1000h	L : Lower specification	n=22,C=0
Low temp. storage	-55°C, 1000h	limit	n=22,C=0
Operation life	I _F =10mA, Ptot=170mW Ta=25°C, 1000h		n=22,C=0

*1 Test method, conforms to EIAJ ED 4701.

- *2 Solder shall adhere at the area of 95% or more of immersed portion of lead, and pin hole or other holes shall not be concentrated on one portion.
- *3 Terminal bending direction is shown below.



- 5. Outgoing inspection
 - 5.1 Inspection items
 - (1) Electrical characteristics

V_F, I_R, I_{CEO}, V_{CE(sat)}, Ic, Riso, Viso

- (2) Appearance
- 5.2 Sampling method and Inspection level

A single sampling plan, normal inspection level II based on ISO 2859 is applied. The AQL according to the inspection items are shown below.

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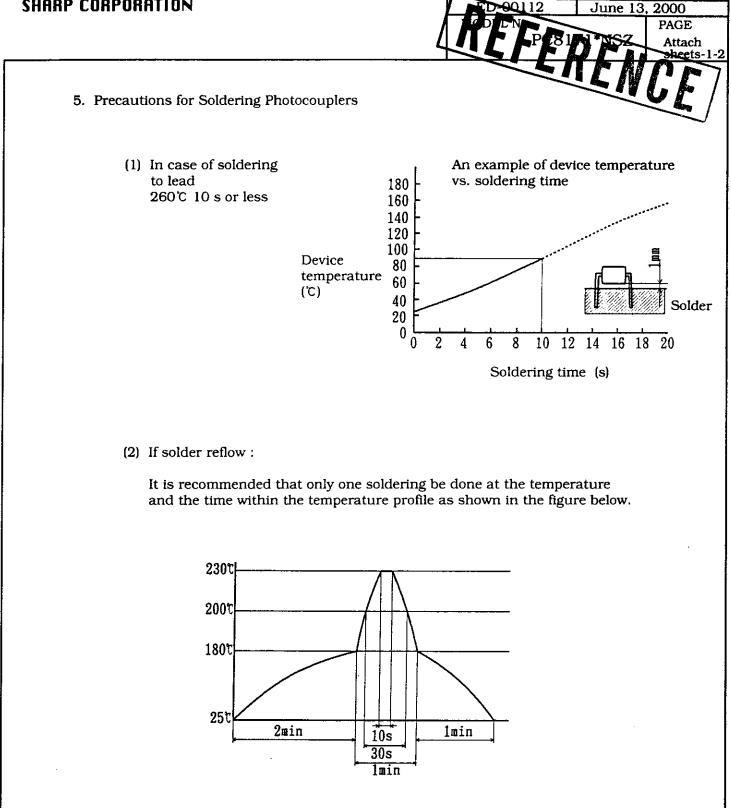
Defect	Inspection item	AQL (%)
Major defect	Electrical characteristics Unreadable marking	0.065
Minor defect	Appearance defect except the above mentioned.	0.25



- 1 For cleaning
 - (1) Solvent cleaning : Solvent temperature 45°C or less Immersion for 3 min or less
 - (2) Ultrasonic cleaning : The effect to device by ultrasonic cleaning differs by cleaning bath size, ultrasonic power output, cleaning time, PCB size or device mounting condition etc. Please test it in actual using condition and confirm that doesn't occur any defect before starting the ultrasonic cleaning.
 - (3) Applicable solvent : Ethyl alcohol, Methyl alcohol, Isopropyl alcohol

In case when the other solvent is used, there are cases that the packaging resin is eroded. Please use the other solvent after thorough confirmation is performed in actual using condition.

- 2. The LED used in the Photocoupler generally decreases the light emission power by operation. In case of long operation time, please design the circuit with considering the degradation of the light emission power of the LED. (50%/5years)
- 3. There are cases that the deviation and temperature dependence of the CTR and the degradation of the light emission power of the LED become big at I_F is less than 0.5mA. Please design the circuit with considering this point.
- 4. When steep voltage noise is applied between the primary side and the secondary side of the photocoupler, current flows or changes in the light emitting diode through a parasitic capacitance between the primary side and the secondary side of the photocoupler, then there is a case that miss operation occurs depending upon the applied noise level. We should certainly recommend to use a by-pass capacitor between both terminals of the light emitting diode where used in a noisy environment.



(3) Other precautions

An infrared lamp used to heat up for soldering may cause a localized temperature rise in the resin. So keep the package temperature within that specified in Item (2). Also avoid immersing the resin part in the solder.

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